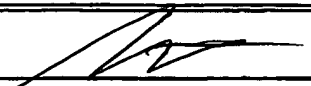


FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. 3944-13-CIP-1	SERIAL NO. Not Yet Assigned
	APPLICANT MAGILL et al.	
	FILING DATE Herewith	GROUP ART

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROP.
<i>cn</i>	1	6,472,885	10/29/2002	Green et al.	324	638	
	2	10/102,614		Magill			3/19/2002
	3	09/815,342		Van Doren et al.			3/21/2001
	4	6,043,308	3/28/2000	Tanahashi et al.	524	495	
	5	5,996,006	11/30/1999	Speicher	709	218	
	6	5,961,913	10/5/1999	Haase	264	326	
	7	5,898,309	4/27/199	Becker et al.	324	689	
	8	5,874,832	2/23/1999	Gabelich	324	688	
	9	5,872,447	2/16/1999	Hager, III	324	71.1	
	10	5,749,986	5/12/1998	Wyatt	156	64	
	11	5,569,591	10/29/1996	Kell et al.	435	29	
	12	5,528,155	6/18/1996	King et al.	324	713	
	13	5,521,515	5/28/1996	Campbell	324	674	
	14	5,486,319	1/23/1996	Stone et al.	264	406	
	15	5,459,406	10/17/1995	Louge	324	688	
	16	5,453,689	9/26/1995	Goldfine et al.	324	239	
	17	5,317,252	5/31/1994	Kranbuehl	324	71.7	
	18	5,283,731	2/1/1994	Latonde et al.	364	401	
	19	5,223,796	6/29/1993	Waldman et al.	324	687	
	20	5,219,498	6/15/1993	Keller et al.	264	40.2	
	21	5,208,544	5/4/1993	McBrearty et al.	324	687	
	22	5,207,956	5/4/1993	Kline et al.	264	40.6	
	23	5,201,956	4/13/1993	Humphrey et al.	118	716	
	24	5,184,077	2/2/1993	Day et al.	324	693	
	25	5,032,525	7/16/1991	Lee et al.	436	55	
	26	5,008,307	4/16/1991	Inomata	523	220	

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	APPLICANT MAGILL et al.	
	FILING DATE Herewith	GROUP ART

<i>m</i>	27	4,881,025	11/4/189	Gregory	324	61 R	
	28	4,868,769	9/19/1989	Persson	364	550	
	29	4,777,431	10/11/1988	Day et al.	324	61 P	
	30	4,773,021	9/20/1988	Harris et al.	364	476	
	31	4,723,908	2/9/1988	Kranbuehl	432	37	
	32	4,676,101	6/30/1987	Baughman	73	304 C	
	33	4,551,807	Nov. 5, 1985	Hsich et al.	364	473	
	34	4,551,103	11/5/1985	Vitale	434	225	
	35	4,515,545	5/7/1985	Hinrichs et al.	425	143	
	36	4,510,436	4/9/1985	Raymond	324	61 P	
	37	4,510,103	4/9/1985	Yamaguchi et al.	264	40.2	
	38	4,496,697	1/29/1985	Zsolnay et al.	526	60	
	39	4,448,943	5/15/1984	Golba et al.	526	59	
	40	4,433,286	2/21/1984	Capots et al.	324	61 R	
	41	4,423,371	12/27/1983	Senturia et al.	324	61 R	
	42	4,399,100	8/16/1983	Zsolnay et al.	422	62	
	43	4,381,250	4/26/1983	Rittenhouse	252	182.1	
	44	4,373,092	2/8/1983	Zsolnay	528	481	
	45	4,344,142	8/10/1982	Diehr, II et al.	364	473	
	46	4,338,163	7/6/1982	Rittenhouse	204	2.1	
	47	4,331,516	5/25/1982	Melghan	204	2.1	
	48	3,985,712	10/12/1976	Garst	260	75 M	
	49	3,879,644	4/22/1975	Malthy	317	246	
	50	3,781,672	12/25/1973	Malthy et al.	324	61 R	
	51	3,778,705	12/11/1973	Malthy	324	61 R	
	52	3,753,092	8/14/1973	Ludlow et al.	324	61 R	
	53	3,746,975	7/17/1973	Malthy	324	65 R	
	54	2,765,219	10/2/1956	Shawhan	23	253	

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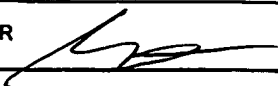
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
							YES	NO
52	55	EP 1 050 888 A1	Nov. 3, 2000	Europe	H01B	1/20		
53	56	EP 0 743 153 A1	Nov. 20, 1996	Europe	B29C	35/02		
54	57	EP 0 540 103 B1	Feb. 7, 1996	Europe	C08K	5/3415		
55	58	WO 99/13346	Mar. 18, 1999	PCT	G01R	27/04		


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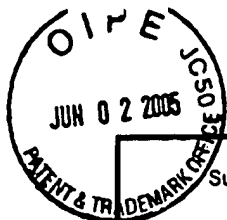
56	59	*Automatic, Computer Controlled, Processing of Advanced Composites"; <i>Defense Small Business Innovation Research (SBIR) Program</i> ; April 7, 1988; 25 pgs.						
57	60	Baumgartner et al.; "Computer Assisted Dielectric Cure Monitoring in Material Quality and Cure Process Control"; <i>SAMPE Journal</i> ; July/August 1983; pgs. 6-16						
58	61	Buczek; "Considerations In the Dielectric Analysis of Composites"; <i>40th International SAMPE Symposium</i> ; May 8-11, 1995; pgs. 696-710						
59	62	Buczek; "Self-Directed Process Control System for Epoxy Matrix Composites"; <i>40th International SAMPE Symposium</i> ; May 8-11, 1995; 8 pgs.						
60	63	"Critical Point Control/Statistical Quality Control Software Module"; <i>Micromet Instruments</i> ; 1993; 2 pgs.						
61	64	Desanges; "Changes in the Electrical Properties of Natural Rubber/Carbon Black Compounds During Vulcaniation"; <i>Revue Generale du Caoutchouc</i> ; December 1957; 34(12); pgs. 631-649						
62	65	"Dielectric Cure Testing on Polyester Bulk Molding Compound"; <i>Holometrix Micromet</i> ; 2001; 3 pgs.; http://www.holometrix.com/holometrix/materialtest.asp						
63	66	"Dielectric Sensors"; <i>NETZSCH</i> ; February 21, 2002; pgs.						
64	67	"Eumetric System III Microdielectrometer..."; <i>Holometrix Micromet</i> ; 2001; 5 pgs.						
65	68	"ICAM-1000 - In-mold Monitoring For SPC, SQC, and CPC (Critical Point Control) of Thermoset Molding Operations"; <i>Micromet Instruments, Inc.</i> ; at least as early as March 1990; 4 pgs.						
66	69	"ICAM-1000 Industrial Cure Analysis & Monitoring System"; <i>Micromet Instruments, Inc.</i> ; August 1, 1991; 1 pg.						
67	70	"ICAM-2000 Multi-Channel Cure Analyzer"; <i>Micromet Instruments</i> ; 1993; 2 pgs.						
68	71	Johnson et al.; "Production Implementation of Fully Automated, Closed Loop cure Control for Advanced Composite Structures"; <i>34th International SAMPE Symposium</i> ; May 8-11, 1989; pgs. 373-384						

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73	Keller et al.; "Real Time, In-Situ Dielectric Monitoring of Advanced Composites Curing Processes"; <i>Programmed Composites, Inc.</i> ; August 1, 1987; 63 pgs.
74	Khastgir; "A Comparative Study of Step Curing and Continuous Curing Methods"; <i>Rubber World</i> ; January 1994; pgs. 28-31
75	"Lockheed Signature Process Control for Composites Proposal"; <i>Ketema Programmed Composites, Inc.</i> ; July 1, 1993; pgs. 1-12
76	"MDE Series 10 Cure Monitor"; <i>Holometrix Micromet</i> ; at least as early as March 15, 2000; 2 pgs.
77	"Mono-Probe"; <i>TYT-NAM-MON</i> ; October 27, 2000; 1 pg.
78	"Northrop Aircraft Division RTM System Proposal"; <i>Ketema Programmed Composites, Inc.</i> ; April 1, 1993; 13 pgs.
79	"Notification of Transmittal of the International Search Report or the Declaration" from the Patent Cooperation Treaty in International Patent Application No. PCT/US02/32480 filed October 9, 2002.
80	O'Connor et al.; "Update to the June 1990 Confidential Descriptive Memorandum"; <i>Micromet Instrument, Inc.</i> ; December 1, 1990; 17 pgs.
81	Persson; "A Novel Method of Measuring Cure - Dielectric Vulcanetry"; <i>Plastics and Rubber Processing and Applications</i> ; 1987; 7(2); pgs. 111-125
82	"Product Selection Grid"; <i>Holometrix Micromet</i> ; 2001; 1 pg.; http://www.holometrix.com/holometrix/m_pgrid.asp
83	Rajeshwar; "AC Impedance Spectroscopy of Carbon Black-Rubber Composites"; <i>Department of Chemistry and Biochemistry at The University of Texas at Arlington</i> ; September 21-24, 1999; 13 pgs.
84	SmartTrac Advertisement, <i>Automotive News</i> ; May 21, 2001, 1 pg.
85	"SmartTrac"; <i>Innovative Aftermarket Systems, Inc.</i> ; 2001; 2 pgs. http://www.ias-inc.net/pages/products/smart.html
86	"Textron Aerostructures Autoclave Process Control Proposal"; <i>Ketema Programmed Composites, Inc.</i> ; February 12, 1993; 16 pgs.
87	"The Eumetric System III Microdielectrometer"; <i>Micromet Instruments, Inc.</i> ; September 1991; 4 pgs.
88	"Thermokinetics"; <i>NETZSCH</i> ; November 8, 2001; 2 pgs.
89	"Tool Mount Sensors"; <i>NETZSCH</i> ; February 21, 2002; 2 pgs.
90	"Vulcanization of Natural Rubber"; <i>NETZSCH</i> ; November 8, 2001; 2 pgs.

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Complete if Known	
				Application Number	10/800,079
				Filing Date	March 11, 2004
				First Named Inventor	Magill et al.
				Art Unit	Not Yet Assigned
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	3944-13-CIP-1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-kind Code ¹ (if known)	Publication Date MM-DD-YYYY	Name of Patentee of Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
<i>av</i>	1	6,855,791	2/15/2005	Van Doren et al.	
<i>w</i>	2	6,774,643	8/10/2004	Magill	
<i>u</i>	3	2004-0133301-A1	7/8/2004	Van Doren et al.	
<i>u</i>	4	4,896,098	1/23/1990	Haritonidis et al.	
<i>u</i>	5	4,710,550	12/1/1987	Kranbuehl	
<i>u</i>	6	11/077,915		Schneider et al.	Filed 3/11/2005

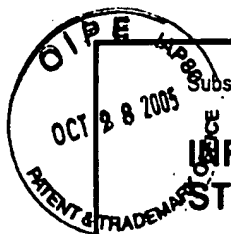
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Examiner Initials*	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁵
		Country Code ² ; Number ³ ; Kind Code ⁴ (if known)					
	7	EP	0 313 435	4/26/1989			
	8	FR	2 645 275	10/5/1990			
	9	WO	04/004998	1/15/2004			
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Examiner Initials*	Cite No. ¹	
<i>u</i>	10	Day; "Cure Characterization of Thick Polyester Composite Structures Using Dielectric and Finite Difference Analysis"; <i>Composite Material Technology</i> ; ASME; 1993; PD-Vol. 53:249-252
<i>u</i>	11	"Prepreg Cure Characterization Using Simultaneous Dynamic Mechanical Analysis-Dielectric Analysis (DMA-DEA); <i>Perkin Elmer Thermal Analysis Newsletter</i> ; (date unknown); 4 pp.
<i>u</i>	12	"Tool Mount Sensors"; http://www.micromet.com/home/rds.htm ; (date unknown); 2 pp.

Examiner Signature		Date Considered	7/27/06
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				Filing Date	March 11, 2004
				First Named Inventor	MAGILL et al.
				Art Unit	Not Yet Assigned
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Sheet	1	of	1	Attorney Docket Number	3944-13-CIP-1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-kind Code ^{1 (if known)}	Publication Date MM-DD-YYYY	Name of Patentee of Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
<i>SV</i>	1	6,490,501	12/2002	Sanders	
<i>V</i>	2	5,210,499	5/1993	Walsh	

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		Country Code ²	Number ²	Kind Code ³ (if known)				
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OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)		
Examiner Initials*	Cite No. ¹	

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